

Notice of References Cited	Application/Control No. 10/707,205		Applicant(s)/Patent Under Reexamination PILEGGI ET AL.	
	Examiner Cynthia Britt		Art Unit 2117	Page 1 of 1

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*	B	US-4,823,136	04-1989	Nathanson et al.	342/368
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	V	"Measurement Challenges for on-wafer RF-SOC test" by Wai Yuen Lau This paper appears in: 27th Annual IEEE/SEMI International Electronics Manufacturing Technology Symposium, 2002. Publication Date: 2002 On page(s): 353- 359 ISBN: 0-7803-7301-4 INSPEC Accession Number: 7492523
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.